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1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

FEATURES

- 1.8-V Phase Lock Loop Clock Driver for Double Data Rate (DDR II) Applications
- Spread Spectrum Clock Compatible
- Operating Frequency: 10 MHz to 340 MHz
- Low Current Consumption: <115 mA
- Low Jitter (Cycle-Cycle): ± 30 ps
- Low Output Skew: 25 ps
- Low Period Jitter: ± 20 ps
- Low Dynamic Phase Offset: ± 15 ps
- Low Static Phase Offset: ± 50 ps
- Distributes One Differential Clock Input to Ten Differential Outputs
- 52-Ball μ BGA (MicroStar™ Junior BGA, 0,65-mm pitch)
- External Feedback Pins (FBIN, $\overline{\text{FBIN}}$) are Used to Synchronize the Outputs to the Input Clocks
- Fail-Safe Inputs

DESCRIPTION

The CDCU877B is a high-performance, low-jitter, low-skew, zero-delay buffer that distributes a differential clock input pair (CK, $\overline{\text{CK}}$) to ten differential pairs of clock outputs (Yn, $\overline{\text{Yn}}$) and to one differential pair of feedback clock outputs (FBOU, $\overline{\text{FBOU}}$). The clock outputs are controlled by the input clocks (CK, $\overline{\text{CK}}$), the feedback clocks (FBIN, $\overline{\text{FBIN}}$), the LVC MOS control pins (OE, OS), and the analog power input (AV_{DD}). When OE is low, the clock outputs, except FBOU/ $\overline{\text{FBOU}}$, are disabled while the internal PLL continues to maintain its locked-in frequency. OS (output select) is a program pin that must be tied to GND or V_{DD}. When OS is high, OE functions as previously described. When OS and OE are both low, OE has no effect on Y7/ $\overline{\text{Y7}}$, they are free running. When AV_{DD} is grounded, the PLL is turned off and bypassed for test purposes.

When both clock inputs (CK, $\overline{\text{CK}}$) are logic low, the device enters in a low power mode. An input logic detection circuit on the differential inputs, independent from input buffers, detects the logic low level and performs in a low power state where all outputs, the feedback, and the PLL are off. When the clock inputs transition from being logic low to being differential signals, the PLL turns back on, the inputs and the outputs are enabled, and the PLL obtains phase lock between the feedback clock pair (FBIN, $\overline{\text{FBIN}}$) and the clock input pair (CK, $\overline{\text{CK}}$) within the specified stabilization time.

The CDCU877B is able to track spread spectrum clocking (SSC) for reduced EMI. This device operates from -40°C to 85°C .

ORDERING INFORMATION

T _A	52-BALL BGA ⁽¹⁾
-40°C to 70°C	CDCU877BZQL

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



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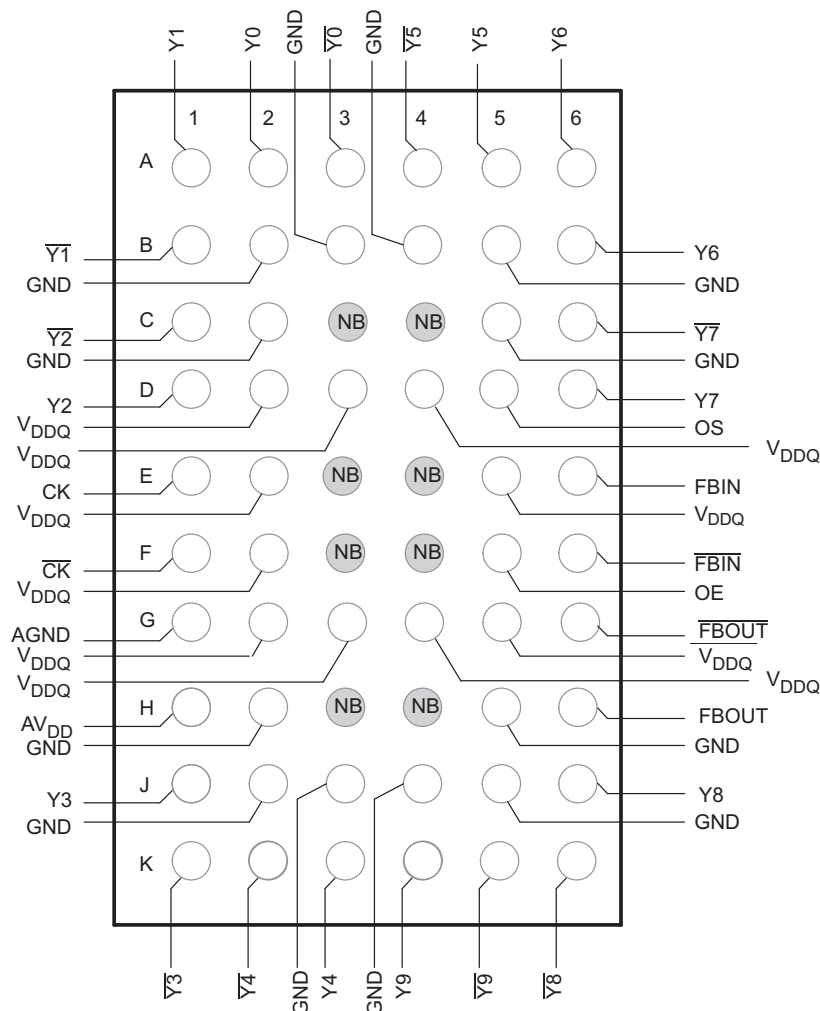
1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

**MicroStar Junior (ZQL) Package
(TOP VIEW)**



- A. NC = No Connection
- B. NB = No Ball

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B–JUNE 2005–REVISED JULY 2007

TERMINAL FUNCTIONS

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
AGND	G1		Analog ground
AV _{DD}	H1		Analog power
CK	E1	I	Clock input with a (10 kΩ to 100 kΩ) pulldown resistor
$\overline{\text{CK}}$	F1	I	Complementary clock input with a (10 kΩ to 100 kΩ) pulldown resistor
FBIN	E6	I	Feedback clock input
$\overline{\text{FBIN}}$	F6	I	Complementary feedback clock input
FBOUT	H6	O	Feedback clock output
$\overline{\text{FBOUT}}$	G6	O	Complementary feedback clock output
OE	F5	I	Output enable (asynchronous)
OS	D5	I	Output select (tied to GND or V _{DD})
GND	B2, B3, B4, B5, C2, C5, H2, H5, J2, J3, J4, J5		Ground
V _{DDQ}	D2, D3, D4, E2, E5, F2, G2, G3, G4, G5		Logic and output power
Y[0:9]	A2, A1, D1, J1, K3, A5, A6, D6, J6, K4	O	Clock outputs
$\overline{\text{Y}}[0:9]$	A3, B1, C1, K1, K2, A4, B6, C6, K6, K5	O	Complementary clock outputs

FUNCTION TABLE

INPUTS					OUTPUTS				
AVDD	OE	OS	CK	$\overline{\text{CK}}$	Y	$\overline{\text{Y}}$	FBOUT	$\overline{\text{FBOUT}}$	PLL
GND	H	X	L	H	L	H	L	H	Bypassed/Off
GND	H	X	H	L	H	L	H	L	Bypassed/Off
GND	L	H	L	H	L _Z	L _Z	L	H	Bypassed/Off
GND	L	L	H	L	L _Z Y7 Active	L _Z $\overline{\text{Y}}7$ Active	H	L	Bypassed/Off
1.8 V Nominal	L	H	L	H	L _Z	L _Z	L	H	On
1.8 V Nominal	L	L	H	L	L _Z Y7 Active	L _Z $\overline{\text{Y}}7$ Active	H	L	On
1.8 V Nominal	H	X	L	H	L	H	L	H	On
1.8 V Nominal	H	X	H	L	H	L	H	L	On
1.8 V Nominal	X	X	L	L	L _Z	L _Z	L _Z	L _Z	Off
X	X	X	H	H	Reserved				

CDCU877B

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

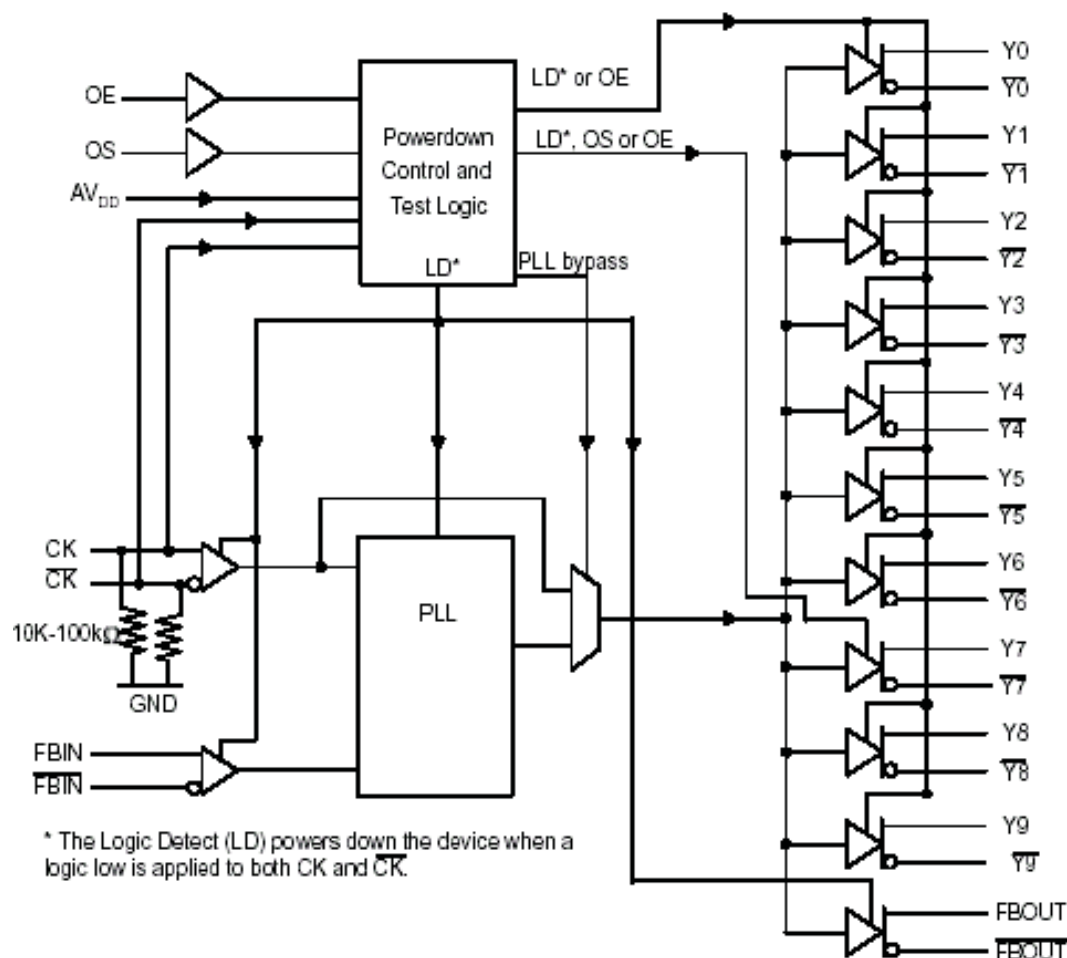


Figure 1. LOGIC DIAGRAM (POSITIVE LOGIC)

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B–JUNE 2005–REVISED JULY 2007

Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range	V _{DDQ} or AV _{DD}	–0.5	2.5	V
V _I	Input voltage range ⁽²⁾⁽³⁾	V _I	–0.5	2.5	V
V _O	Output voltage range ⁽²⁾⁽³⁾	V _O	–0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0 or V _I > V _{DDQ}		±50	mA
I _{OK}	Output clamp current	V _O < 0 or V _O > V _{DDQ}		±50	mA
I _O	Continuous output current	V _O = 0 to V _{DDQ}		±50	mA
	Continuous current through each V _{DDQ} or GND			±100	mA
T _{stg}	Storage temperature range		–65	150	°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) This value is limited to 2.5 V maximum.

Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V _{CC}	Output supply voltage, V _{DDQ}		1.7	1.8	1.9	V
	Supply Voltage, AV _{DD}			V _{DDQ}		V
V _I	Input voltage ⁽¹⁾				V _{CC}	V
V _{IL}	Low-level input voltage ⁽²⁾	OE, OS			0.35 x V _{DDQ}	V
V _{IH}	High-level input voltage ⁽²⁾	CK, $\overline{\text{CK}}$	0.65 x V _{DDQ}			V
I _{OH}	High-level output current				–9	mA
I _{OL}	Low-level output current (see Figure 2)				9	mA
V _{IX}	Input differential-pair cross voltage (see Figure 2)		(V _{DDQ} /2) – 0.15		(V _{DDQ} /2) + 0.15	V
V _I	Input voltage level		–0.3		V _{DDQ} + 0.3	V
V _{ID}	Input differential voltage ⁽²⁾ (see Figure 9)	DC	0.3		V _{DDQ} + 0.4	V
		AC	0.63		V _{DDQ} + 0.4	V
T _A	Operating free-air temperature		–40		85	°C

- (1) The PLL is turned off and bypassed for test purposes when AV_{DD} is grounded. During this test mode, V_{DDQ} remains within the recommended operating conditions and no timing parameters are specified.
- (2) V_{ID} is the magnitude of the difference between the input level on CK and the input level on $\overline{\text{CK}}$, see Figure 9 for definition. The CK and $\overline{\text{CK}}$, V_{IH} and V_{IL} limits define the dc low and high levels for the logic detect state.

CDCU877B

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS	AV _{DD} , V _{DDQ}	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IK}	Input		I _I = 18 mA	1.7			-1.2	V
V _{OH}	High-level output voltage		I _{OH} = -100 µA	1.7 to 1.9	V _{DDQ} - 0.2			V
			I _{OH} = -9 mA	1.7	1.1			
V _{OL}	Low-level output voltage		I _{OL} = 100 µA				0.1	V
			I _{OL} = 9 mA	1.7			0.6	
I _{O(DL)}	Low-level output current, dissabled		V _{O(DL)} = 100 mV, OE = L	1.7	100			µA
V _{OD}	Differential output voltage ⁽¹⁾			1.7	0.5			V
I _I	Input current	CK, $\overline{\text{CK}}$		1.9	±250			µA
		OE, OS, FBIN, $\overline{\text{FBIN}}$		1.9	±10			
I _{DD(LD)}	Supply current, static (I _{DDQ} + I _{ADD})		CK and $\overline{\text{CK}}$ = L	1.9	500			µA
I _{DD}	Supply current, dynamic (I _{DDQ} + I _{ADD}) (see Note ⁽²⁾ for CPD calculation)		CK and $\overline{\text{CK}}$ = 270 MHz. All outputs are open (not connected to a PCB)	1.9	115			mA
			All outputs are loaded with 2 pF and 120-Ω termination resistor	1.9	215			
			All outputs are loaded with 10 pF and 120-Ω termination resistor	1.9	235			
C _I	Input capacitance	CK, $\overline{\text{CK}}$	V _I = V _{DD} or GND	1.8	2		3	pF
		FBIN, $\overline{\text{FBIN}}$		1.8	2		3	
C _{I(Δ)}	Change in input current	CK, $\overline{\text{CK}}$	V _I = V _{DD} or GND	1.8	0.25			
		FBIN, $\overline{\text{FBIN}}$		1.8	0.25			

(1) V_{OD} is the magnitude of the difference between the true and complimentary outputs. See Figure 9 for a definition.

(2) Total I_{DD} = I_{DDQ} + I_{ADD} = f_{CK} × C_{PD} × V_{DDQ}, solving for C_{PD} = (I_{DDQ} + I_{ADD})/(f_{CK} × V_{DDQ}) where f_{CK} is the input frequency, V_{DDQ} is the power supply, and C_{PD} is the power dissipation capacitance.

Timing Requirements⁽¹⁾

over recommended operating free-air temperature range (unless otherwise noted) (see)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
f _{CK}	Clock frequency (operating) ⁽¹⁾⁽²⁾	AV _{DD} , V _{DD} = 1.8 V ±0.1 V	10	340	MHz
	Clock frequency (application) ⁽¹⁾⁽³⁾		160	340	MHz
t _{DC}	Duty cycle, input clock		40%	60%	
t _L	Stabilization time ⁽⁴⁾			12	µs

(1) The PLL must be able to handle spread spectrum induced skew.

(2) Operating clock frequency indicates a range over which the PLL must be able to lock, but in which it is not required to meet the other timing parameters (used for low speed system debug).

(3) Application clock frequency indicates a range over which the PLL must meet all timing parameters.

(4) Stabilization time is the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power up. During normal operation, the stabilization time is also the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal when CK and $\overline{\text{CK}}$ go to a logic low state, enter the power-down mode and later return to active operation. CK and $\overline{\text{CK}}$ may be left floating after they have been driven low for one complete clock cycle.

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B–JUNE 2005–REVISED JULY 2007

Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see ⁽¹⁾) AV_{DD} , $V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{en}	Enable time, OE to any $\overline{Y}/\overline{Y}$	See Figure 11			8	ns
t_{dis}	Disable time, OE to any $\overline{Y}/\overline{Y}$	See Figure 11			8	ns
$t_{jit(cc+)}$ $t_{jit(cc-)}$	Cycle-to-cycle period jitter ⁽²⁾	160 MHz to 200 MHz, see Figure 4	0		± 40	ps
		200 MHz to 270 MHz, see Figure 4	0		± 35	
		270 MHz to 340 MHz, see Figure 4	0		± 30	
$t_{(u)}$	Static phase offset time ⁽³⁾	See Figure 5	-50		50	ps
$t_{(u)dyn}$	Dynamic phase offset time	See Figure 10	-15		15	ps
$t_{sk(o)}$	Output clock skew	See Figure 6			25	ps
$t_{jit(per)}$	Period jitter ⁽⁴⁾⁽²⁾	160 MHz to 200 MHz, see Figure 7	-30		30	ps
		201 MHz to 340 MHz, see Figure 7	-20		20	
$t_{jit(hper)}$	Half-period jitter ⁽⁴⁾⁽²⁾	160 MHz to 190 MHz, see Figure 8		± 90		ps
		190 MHz to 250 MHz, see Figure 8		± 60		
		250 MHz to 340 MHz, see Figure 8		± 40		
SR	Slew rate, OE	See Figure 9	0.5			V/ns
	Input clock slew rate	See Figure 9	1	2.5	4	
	Output clock slew rate ⁽⁵⁾⁽⁶⁾ (no load)	See Figure 9 and Figure 13	1.5	2.5	3	
V_{OX}	Output differential-pair cross voltage ⁽⁷⁾	See Figure 2	$(V_{DDQ}/2) - 0.1$		$(V_{DDQ}/2) + 0.1$	V
	SSC modulation frequency		30		33	kHz
	SSC clock input frequency deviation		0%		-0.5%	
	PLL loop bandwidth		2			MHz

- (1) There are two different terminations that are used with the following tests. The load/board in Figure 2 is used to measure the input and output differential-pair cross voltage only. The load/board in Figure 3 is used to measure all other tests. For consistency, equal length cables must be used.
- (2) This parameter is specified by design and characterization.
- (3) Phase static offset time does not include jitter.
- (4) Period jitter, half-period jitter specifications are separate specifications that must be met independently of each other.
- (5) The output slew rate is determined from the IBIS model with a 120- Ω load only.
- (6) To eliminate the impact of input slew rates on static phase offset, the input skew rates of reference clock input CK and \overline{CK} and feedback clock inputs FBIN and \overline{FBIN} are recommended to be nearly equal. The 2.5-V/ns skew rates are shown as a recommended target. Compliance with these typical values is not mandatory if it can adequately shown that alternative characteristics meet the requirements of the registered DDR2 DIMM application.
- (7) Output differential-pair cross voltage specified at the DRAM clock input or the test load.

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

PARAMETER MEASUREMENT INFORMATION

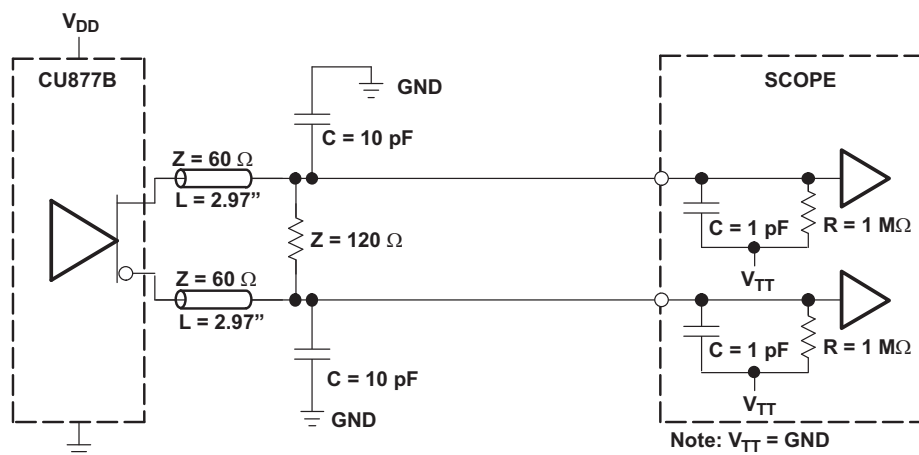


Figure 2. Output Load Test Circuit 1

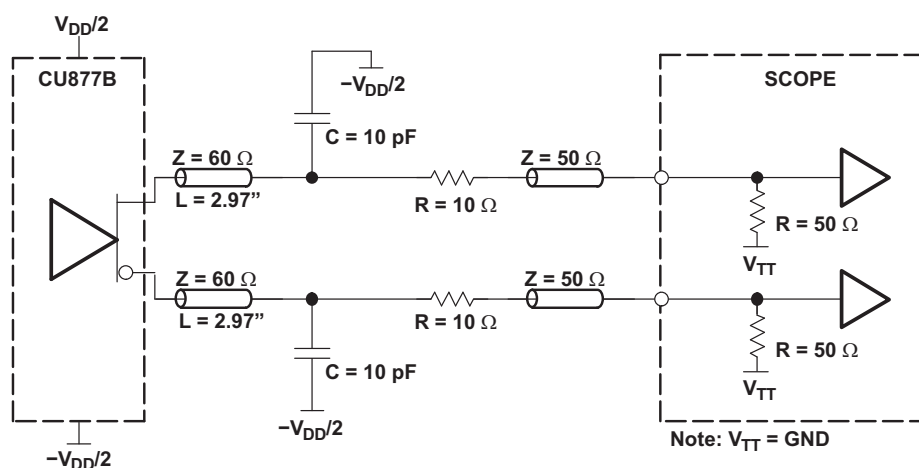


Figure 3. Output Load Test Circuit 2

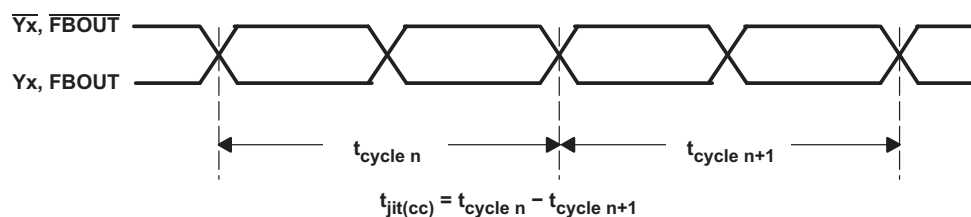


Figure 4. Cycle-To-Cycle Period Jitter

PARAMETER MEASUREMENT INFORMATION (continued)

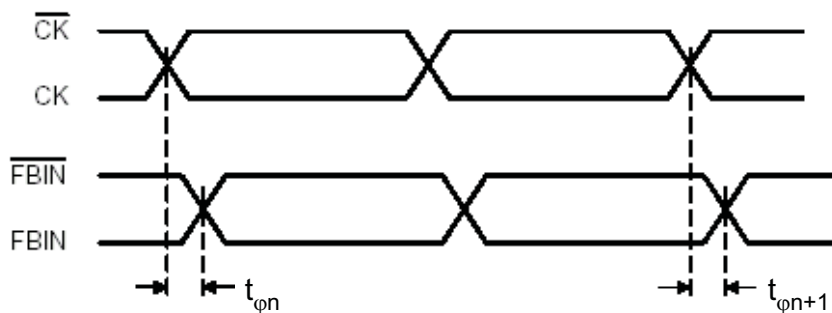


Figure 5. Static Phase Offset

$$t_{\phi} = \frac{\sum_{n=1}^{N} t_{\phi n}}{N}$$

(N is the large number of samples)

(N > 1000 samples)

(1)

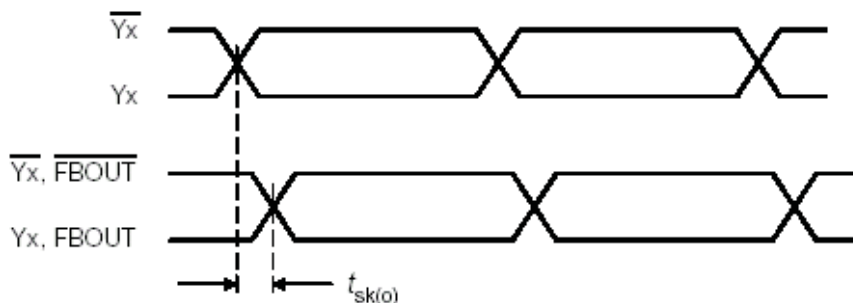


Figure 6. Output Skew

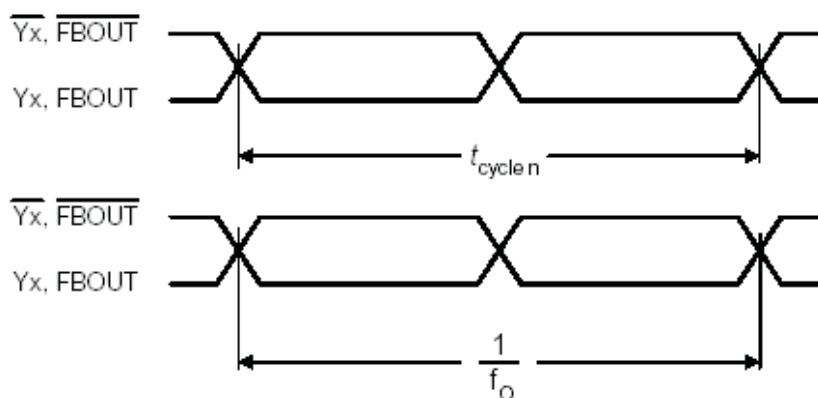


Figure 7. Period Jitter

$$t_{jit(per)} = t_{cycle\ n} - \frac{1}{f_o}$$

(f_o average input frequency measured at CK/CK)

(2)

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

PARAMETER MEASUREMENT INFORMATION (continued)

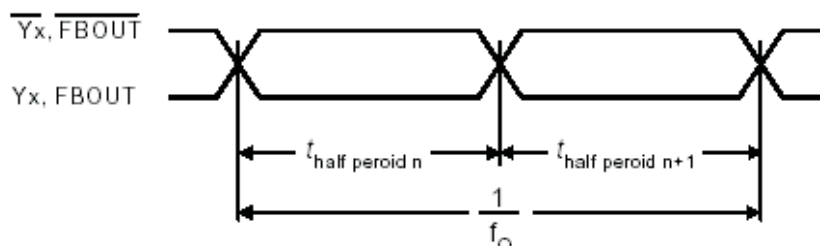


Figure 8. Half-Period Jitter

$$t_{jit(hper)} = t_{half\ period\ n} - \frac{1}{2 \times f_O}$$

n = any half cycle

(f_O average input frequency measured at CK/ \overline{CK})

(3)

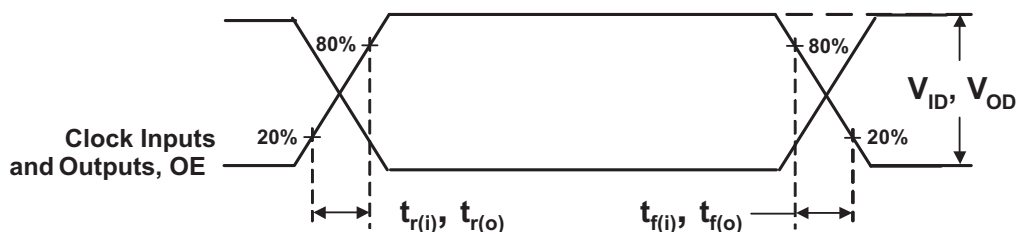


Figure 9. Input and Output Slew Rates

$$slrr_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{r(i/o)}}$$

$$slrf_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{f(i/o)}}$$

(4)

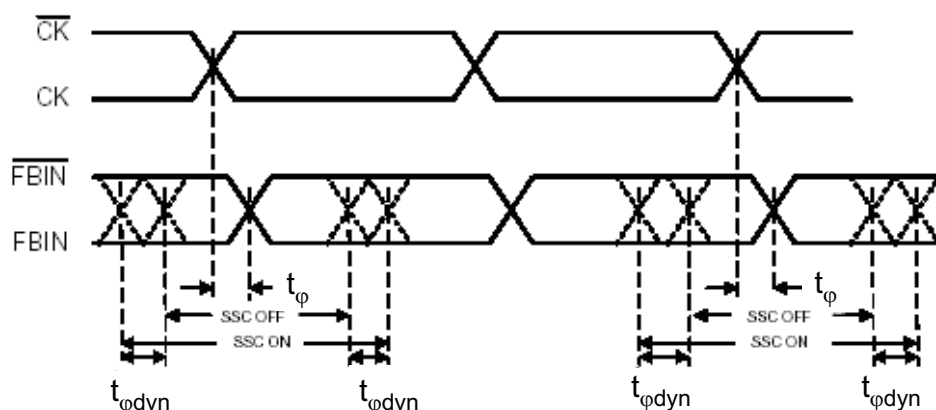


Figure 10. Dynamic Phase Offset

PARAMETER MEASUREMENT INFORMATION (continued)

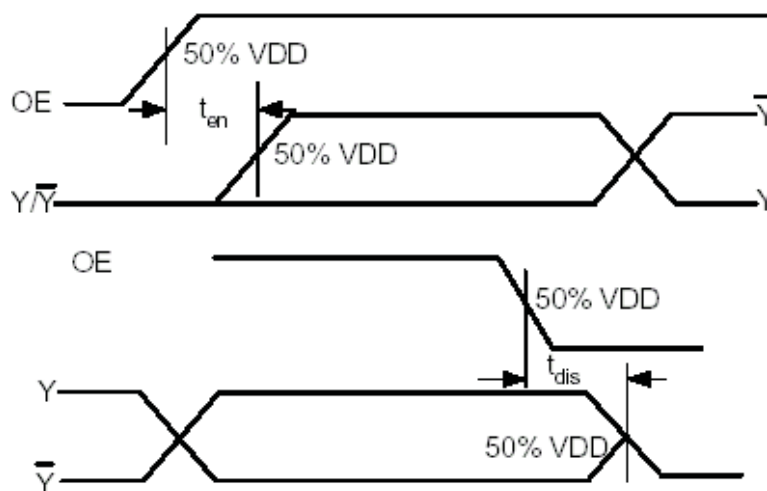
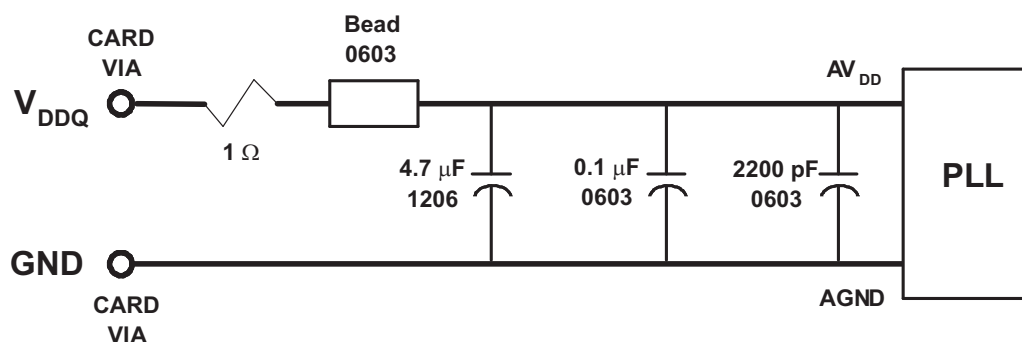


Figure 11. Time Delay Between OE and Clock Output (Y, \bar{Y})

RECOMMENDED AV_{DD} FILTERING



- Place the 2200-pF capacitor close to the PLL.
- Use a wide trace for the PLL analog power and ground. Connect PLL and capacitors to AGND trace and connect trace to one GND via (farthest from the PLL).
- Recommended bead: Fair-Rite PN 2506036017Y0 or equivalent (0.8 Ω dc maximum, 600 Ω at 100 MHz).

Figure 12. Recommended AV_{DD} Filtering

CDCU877B

1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS801B—JUNE 2005—REVISED JULY 2007

PARAMETER MEASUREMENT INFORMATION (continued)

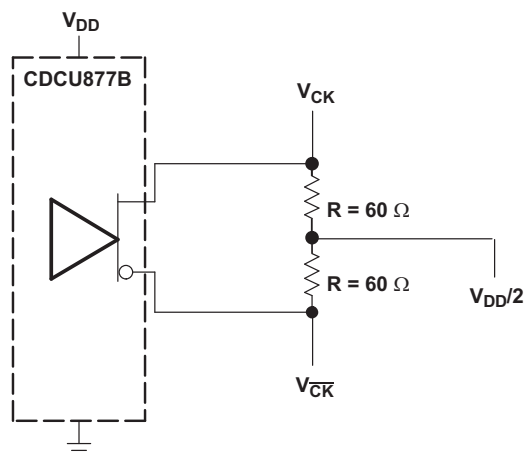


Figure 13.

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
CDCU877BZQLR	ACTIVE	BGA MI CROSTAR JUNIOR	ZQL	52	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR
CDCU877BZQLT	ACTIVE	BGA MI CROSTAR JUNIOR	ZQL	52	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBsolete: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

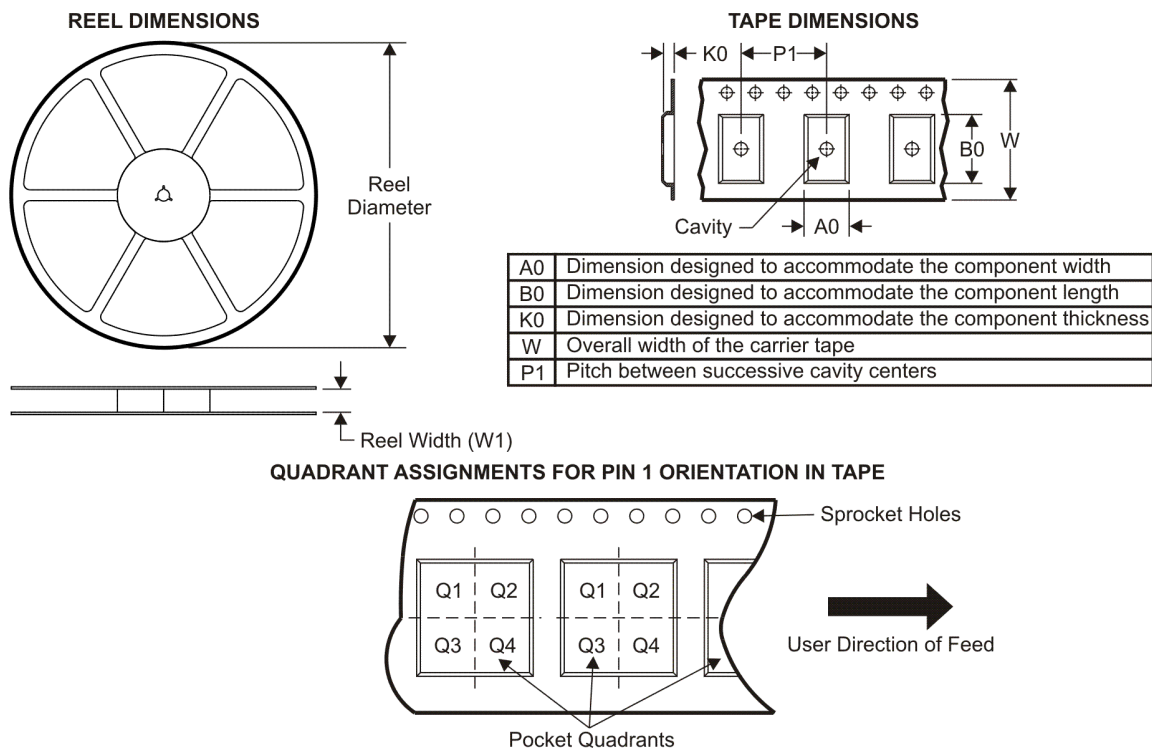
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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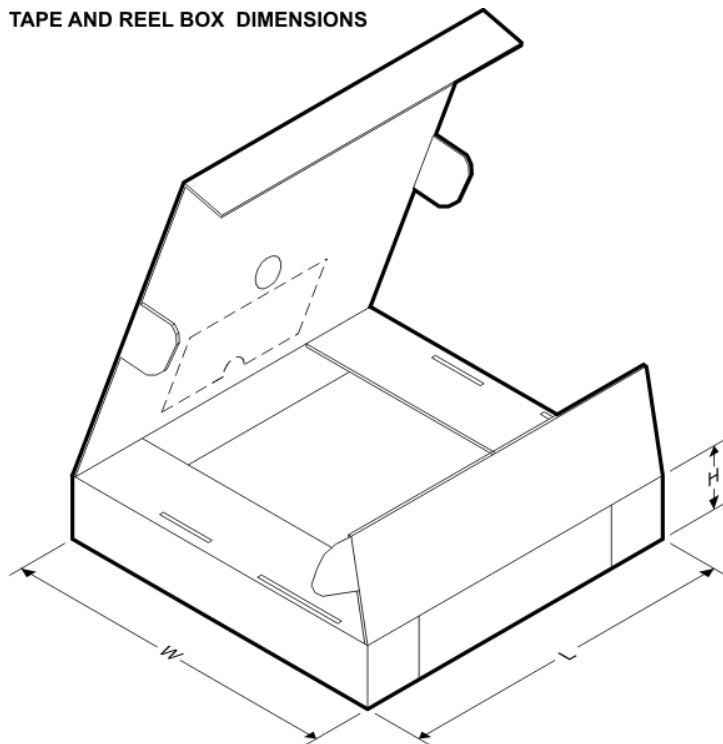
TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCU877BZQLR	BGA MICROSTAR JUNIOR	ZQL	52	1000	330.0	16.4	4.8	7.3	1.5	8.0	16.0	Q1
CDCU877BZQLT	BGA MICROSTAR JUNIOR	ZQL	52	250	330.0	16.4	4.8	7.3	1.5	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



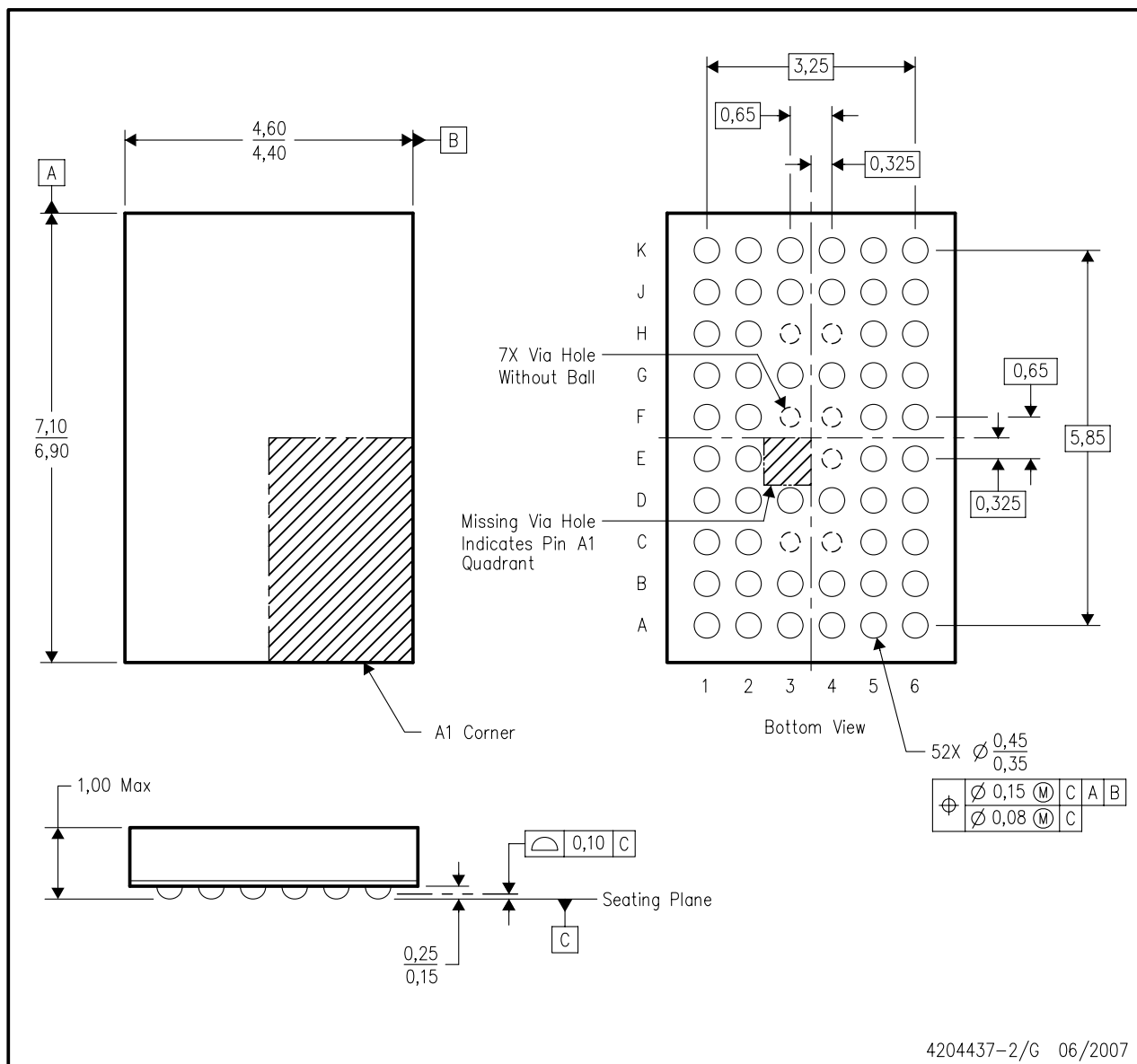
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCU877BZQLR	BGA MICROSTAR JUNIOR	ZQL	52	1000	333.2	345.9	28.6
CDCU877BZQLT	BGA MICROSTAR JUNIOR	ZQL	52	250	333.2	345.9	28.6

MECHANICAL DATA

ZQL (R-PBGA-N52)

PLASTIC BALL GRID ARRAY



- NOTES:
- All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - This drawing is subject to change without notice.
 - Falls within JEDEC MO-285 variation BA-2.
 - This package is lead-free. Refer to the 52 GQL package (drawing 4200583) for tin-lead (SnPb).

IMPORTANT NOTICE

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